ES52F3D20N-18.414M



ES52F3 D 20 N -18.414M

Operating Temperature Range -30°C to +75°C

Frequency Stability ±2.0ppm Maximum

| , | - Nominal Frequency |
|---|---------------------|
| | 18.414MHz |

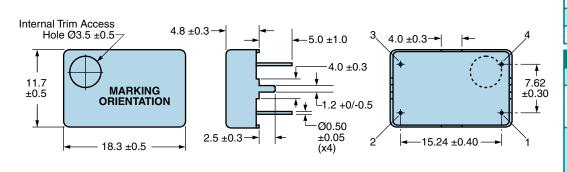
Control Voltage None (No Connect on Pin 1)

| ELECTRICAL SPECIFICATIONS | | |
|---|---|--|
| Nominal Frequency | 18.414MHz | |
| Frequency Stability | ±2.0ppm Maximum (Inclusive of Operating Temperature Range) | |
| Frequency Stability vs. Input Voltage | ±0.3ppm Maximum (±5%) | |
| Aging at 25°C | ±1ppm/Year Maximum | |
| Frequency Stability vs. Load | ±0.2ppm Maximum (±2pF) | |
| Operating Temperature Range | -30°C to +75°C | |
| Supply Voltage | 3.3Vdc ±5% | |
| Input Current | 1.5mA Maximum | |
| Output Voltage | 0.7Vp-p Minimum | |
| Load Drive Capability | 10kOhms//10pF | |
| Output Logic Type | Clipped Sinewave | |
| Control Voltage | None (No Connect on Pin 1) | |
| Internal Trim | ±3ppm Minimum (Top of Can) | |
| Modulation Bandwidth | 10kHz Minimum (Measured at -3dB with a Control Voltage of 1.65Vdc) | |
| Input Impedance | 10kOhms Typical | |
| Phase Noise | -70dBc at 10Hz Offset, -100dBc at 100Hz Offset, -130dBc at 1kHz Offset, -140dBc at 10kHz Offset, - 145dBc at 100kHz Offset | |
| Storage Temperature Range | -40°C to +85°C | |
| ENVIRONMENTAL & MECHANICAL SPECIFICATIONS | | |
| Fine Leak Test | MIL-STD-883, Method 1014 Condition A (Internal Crystal Only) | |
| Gross Leak Test | MIL-STD-883, Method 1014 Condition C (Internal Crystal Only) | |
| Lead Integrity | MIL-STD-883, Method 2004 | |
| Mechanical Shock | MIL-STD-202, Method 213 Condition C | |
| Resistance to Soldering Heat | MIL-STD-202, Method 210 | |
| Resistance to Solvents | MIL-STD-202, Method 215 | |
| Solderability | MIL-STD-883, Method 2003 | |
| Temperature Cycling | MIL-STD-883, Method 1010 | |
| Vibration | MIL-STD-883, Method 2007 Condition A | |



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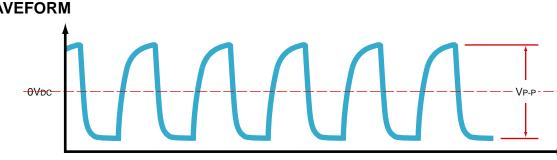
MECHANICAL DIMENSIONS (all dimensions in millimeters)



| PIN | CONNECTION |
|------|---|
| 1 | No Connect |
| 2 | Case/Ground |
| 3 | Output |
| 4 | Supply Voltage |
| LINE | MARKING |
| 1 | ECLIPTEK |
| 2 | 18.414M <i>M</i> =Nominal Frequency Unit of Measure |
| 3 | XXYZZ XX=Ecliptek Manufacturing Code Y=Last Digit of the Year ZZ=Week of the Year |

OUTPUT WAVEFORM

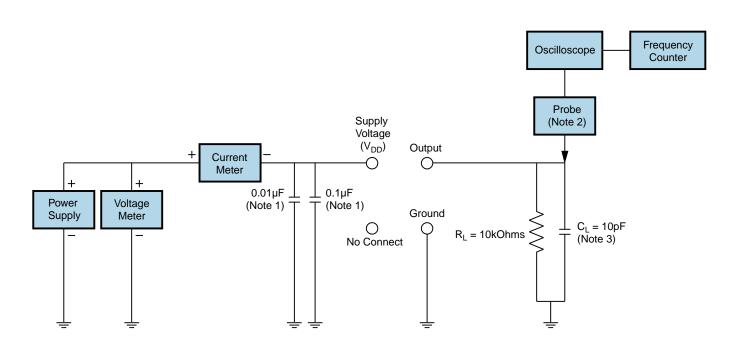
CLOCK OUTPUT



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Test Circuit for No Connect Option



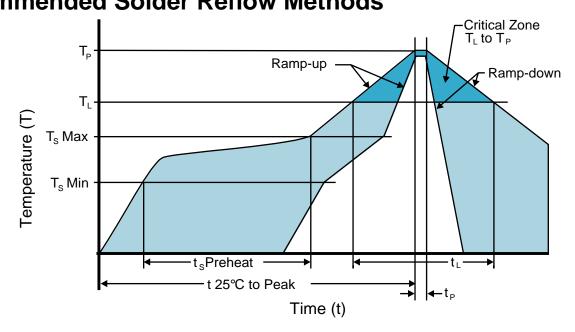
Note 1: An external 0.1µF low frequency tantalum bypass capacitor in parallel with a 0.01µF high frequency ceramic bypass capacitor close to the package ground and V_{DD} pin is required.

Note 2: A low capacitance (<12pF), 10X attenuation factor, high impedance (>10Mohms), and high bandwidth (>300MHz) passive probe is recommended.

Note 3: Capacitance value \dot{C}_{L} includes sum of all probe and fixture capacitance.



ES52F3D20N-18.414M Recommended Solder Reflow Methods



Low Temperature Solder Bath (Wave Solder)

| 5°C/second Maximum |
|---|
| |
| N/A |
| 150°C |
| N/A |
| 30 - 60 Seconds |
| 5°C/second Maximum |
| |
| 150°C |
| 200 Seconds Maximum |
| 245°C Maximum |
| 245°C Maximum 1 Time / 235°C Maximum 2 Times |
| 5 seconds Maximum 1 Time / 15 seconds Maximum 2 Times |
| 5°C/second Maximum |
| N/A |
| Level 1 |
| |

Low Temperature Manual Soldering

185°C Maximum for 10 seconds Maximum, 2 times Maximum.

High Temperature Manual Soldering

260°C Maximum for 5 seconds Maximum, 2 times Maximum.

Low Temperature Solder Bath (Wave Solder) Note 1

Device is non-hermetic; Post reflow aqueous wash is not recommended

Low Temperature Solder Bath (Wave Solder) Note 2

Temperatures shown are applied to back of PCB board and device leads only.